



FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS COMPLETES FINAL FOX-1™ MILESTONE

Fremont, CA (June 20, 2006) – Aehr Test Systems (Nasdaq: AEHR), a leading manufacturer of parallel test and burn-in systems, today announced that it has completed the final milestone in the development of its FOX-1 full wafer, single touchdown parallel tester. A leading IC manufacturer has formally accepted the final milestone, which verifies production readiness of the first FOX-1 system and full wafer contactor.

“This is a major event for Aehr Test, as it validates that our FOX-1 full wafer contact parallel tester is ready for high volume manufacturing,” said Rhea Posedel, chairman and chief executive officer of Aehr Test Systems. “Since our FOX-1 system can parallel test an entire wafer with thousands of die in a single touchdown, we believe that it can significantly increase test throughput and reduce test costs.”

The FOX-1 full wafer parallel test system, a member of the FOX family of full wafer contact systems, is designed to test an entire wafer of devices with a single touchdown or be utilized for short-duration burn-in and test. This innovative solution combines full wafer contact, massively parallel test and Design For Test (DFT) technologies. Other members of Aehr Test’s FOX family of products are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX and MAX systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technology, acceptance by customers of the FOX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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